

High Resolution High Accuracy Semicontact / Noncontact AFM Cantilevers HA_NC series, each chip has 2 cantilevers, resonant frequency 235 kHz / 140 kHz, force constant 12 N/m / 3.5 N/m

Art. ID	TIPS-HA_NC/300
Unit	300 separated chips
Deliverydetails	No Dangerous Good /not restricted

Description

High Resolution High Accuracy AFM Cantilevers HA_NC series are designed for Semicontact (Intermittent), Noncontact applications. Each probe has 2 rectangular cantilevers. Typical Resonant Frequency 235kHz / 140kHz (dispersion $\pm 10\%$). Typical Force Constant 12N/m / 3.5N/m (dispersion $\pm 20\%$). Cantilever has Au reflective side coating t /// increase laser signal. Probes are als /// available with n /// coating as well as with conductive tip coating / Probes are packed in boxes with 15 and 50 pieces. Amount discount is included in the package price / High Accuracy composite ETALON probes combine the main features allowing t /// obtain high quality AFM images: Sharp tip - curvature radius < 10 nm. /// Resonance frequency, specified with high accuracy - $\pm 10\%$ within a wafer. /// Special chip geometry with vertical sidewalls for convenient operating. /// High aspect rati /// tip. /// Enhanced back-side reflection of the cantilever. /// Cost effective price.